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	Application No.	Applicant(s)	Y
	10/764,089	YOSHIKAWA ET A	ıL
Notice of Allowability	Examiner	Art Unit	
	Vinod D. Patel	3742	
The MAILING DATE of this communication apperall claims being allowable, PROSECUTION ON THE MERITS IS herewith (or previously mailed), a Notice of Allowance (PTOL-85) NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RI	(OR REMAINS) CLOSED i or other appropriate comm GHTS. This application is	n this application. If not include unication will be mailed in due	ded e course. THIS
1. X This communication is responsive to papers filed on 1/23/0	<u>14</u> .		
2. ⊠ The allowed claim(s) is/are <u>1-9</u> .			
3. $igotimes$ The drawings filed on 23 January 2004 are accepted by the	e Examiner.		
 4. Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f). a)			
 Attachment(s) 1. ☑ Notice of References Cited (PTO-892) 2. ☐ Notice of Draftperson's Patent Drawing Review (PTO-948) 3. ☑ Information Disclosure Statements (PTO-1449 or PTO/SB/0 Paper No./Mail Date 1/23/04) 4. ☐ Examiner's Comment Regarding Requirement for Deposit of Biological Material 	6. ☐ Interview S Paper No. 8), 7. ☐ Examiner's	nformal Patent Application (PT Summary (PTO-413), ./Mail Date s Amendment/Comment s Statement of Reasons for All 	

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Allowable Subject Matter

1. Claims 1-9 are allowed.

2. The following is an examiner's statement of reasons for allowance:

The prior art of record does not teach to one of ordinary skill in the art, in combination with the other limitations of the independent claims, a glow plug comprising a pair of electric conductors embedded in the ceramic heater so as to electrically connect the resistance-heating element and a first and a second metallic fitting members, one electric conductor having a first exposed portion joined to the first metallic fitting member, and the other electric conductor having a second exposed portion joined to the second metallic fitting member, wherein a metal layer not higher than Ni ionization tendency is formed on an inner circumferential surface of the first metallic fitting member and on an inner circumferential surface of the second metallic fitting member, the inner circumferential surfaces facing the first and second exposed portions, respectively; and the metal layers are in contact with the corresponding first and second exposed portions.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

3. The prior art made of record and not relied upon is considered pertinent to applicant's disclosure. Sato (6483079), Taniguchi (US6326595), Chiu (US6285007), Simpkins (6215105), Chiu (US6177653 & US6144015), Yoshikawa (US6082175), Schmidt (US5645742), Ogata (US4931619), Yoshida (US4475029) relate to glow plugs

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4. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Vinod D. Patel whose telephone number is 703-308-5227. The examiner can normally be reached on 7.30 A.M. TO 4.00 P.M..

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Robin Evans can be reached on 703-305-5766. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

VP September 30, 2004 Vinod Patel
Patent Examiner

ROBIN O. EVANS PRIMARY EXAMINED